



[ThPM2-06] Raman Metrology 2

Date / Time Aug. 30 (Thu.), 2018 / 16:45-18:45

Place 301 (Room E)

[ThPM2-06-K-1] (Keynote)

16:45-17:15

Valid Measurements of Fullerene and Graphene by Raman Spectroscopy

Lingling Ren, Yaxuan Yao, and Xiangyong Sheng

National Institute of Metrology of China, China

[ThPM2-06-I-2] (Invited)

17:15-17:35

Resonant Raman Spectroscopy Captures New Physics in Chirality-Enriched, Single Wall Carbon Nanotubes

Yanmei Piao¹, Jeffrey R. Simpson^{1, 2}, Jason K. Streit¹, Geyou Ao¹, Oleksiy Roslyak³, Erik Haroz⁴, Juan Duque⁴, Jared Crochet⁴, Hagen Telg⁴, Andrei Piryatinski⁴, Stephen Doorn⁴, Ming Zheng¹, Jeffrey A. Fagan¹, and Angela R. Hight Walker¹

¹National Institute of Standards and Technology, USA, ²Towson University, USA, ³Fordham University, USA, ⁴Los Alamos National Laboratory, USA

[ThPM2-06-I-3] (Invited)

17:35-17:55

Towards Traceable Quantitative Measurements with Raman Spectroscopy / Microscopy

Li-Lin Tay, John Hulse, and Shawn Poirier

National Research Council Canada, Canada

[ThPM2-06-I-4] (Invited)

17:55-18:15

Application of Time-Resolved Resonance Raman Spectroscopy to Pulse Radiolysis

Mamoru Fujitsuka

Osaka University, Japan

[ThPM2-06-O-5]

18:15-18:30

Using Raman Spectra to Probe Lattice Strain in TMDC

Ye Zhang¹, Huaihong Guo¹, Teng Yang², and Riichiro Saito³

¹ Liaoning Shihua University, China, ²Chinese Academy of Sciences, China, ³Tohoku University, Japan

[ThPM2-06-O-6]

18:30-18:45

Investigation on the Electric-field-induced Switching Effect of Single Cu-TCNQ Crystals by Polarized Raman Spectroscopy

Yanlong Xing¹, Eugen Speiser¹, Norbert Esser¹, and Petra S. Dittrich²

¹Leibniz-Institut für Analytische Wissenschaften - ISAS, Germany, ²ETH Zurich, Switzerland